


<b>Search Notes</b>  	<b>Application/Control No.</b>  10526492	<b>Applicant(s)/Patent Under Reexamination</b>  EDER ET AL.
	<b>Examiner</b>  RICHARD CHAN	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
600	544, 545, 554, 559	8/24/08	RC
607	55-57	8/24/08	RC

SEARCH NOTES		
Search Notes	Date	Examiner

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner